



银河微电
Galaxy
Microelectronics

股票代码: 688689.SH

常州银河世纪微电子股份有限公司
Changzhou Galaxy Century Microelectronics Co., Ltd.

致力于成为世界知名的 半导体分立器件供应商



AEC

国际汽车电子协会成员



30+ Years

丰富行业经验



1200

员工人数



40,000m²

占地面积



128,400,000

注册资金/人民币

1964-2006年

1964-常州无线电元件七厂成立
1985-引进国内第一条塑封二极管
生产线
1994-常州银河电器有限公司成立

2006-2018 年

2006-香港主板上市：HK0527
常州银河世纪微电子有限公司成立
2015-规模化生产车规产品
2018-正式加入国际汽车电子协会元件
技术委员会

2018-2023 年

2021-上海科创板IPO
股票代码：688689
2022-发行可转债，用于车规级半导体器件产业
化项目

1994 年

投资4吋晶圆生产线

2006 年

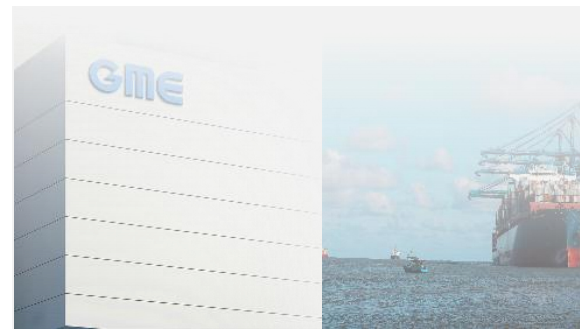
投资6吋晶圆生产线

2014 年

8吋MOS晶圆流片成功

2021 年

12吋MOS晶圆流片成功



常州银河世纪微电子股份有限公司

地址：江苏省常州市新北区长江北路19号

成立时间：2006年

厂房面积：28618.44平方米

主要产品：二极管、三极管、MOSFET、桥堆、光耦、模拟IC等平面工艺晶圆线（6吋）

子公司：常州银河电器有限公司

地址：常州新北区河海西路168号+巢湖路208号

成立时间：1994年

厂房面积：15348.34平方米+8397平方米

主要产品：塑封轴向二极管、玻璃封装二极管

玻璃钝化工艺晶圆线（4吋）

新晶圆厂（筹备中）



海外基地（布局中）

企业荣誉

中国半导体行业功率器件十强企业

江苏省片式半导体分立器件工程技术研究中心

江苏省绿色工厂

浙江大学常州工业技术研究院
产学研基地

江苏省名牌产品

江苏省认定企业技术中心

中国驰名商标

江苏省半导体行业协会理事单位

江苏省高新技术产品

常州市守合同重信用企业

国家“专精特新小巨人”企业

苏南国家自主创新示范区瞪羚企业

江苏省半导体分立器件芯片
及封装工程技术研究中心



数字银河

- ◎ 科创板上市公司，股票代码: **688689**
- ◎ IDM经营管理模式
- ◎ 国内首家半导体分立器件AEC会员单位
- ◎ 国家专精特新“小巨人”
- ◎ 高新技术企业

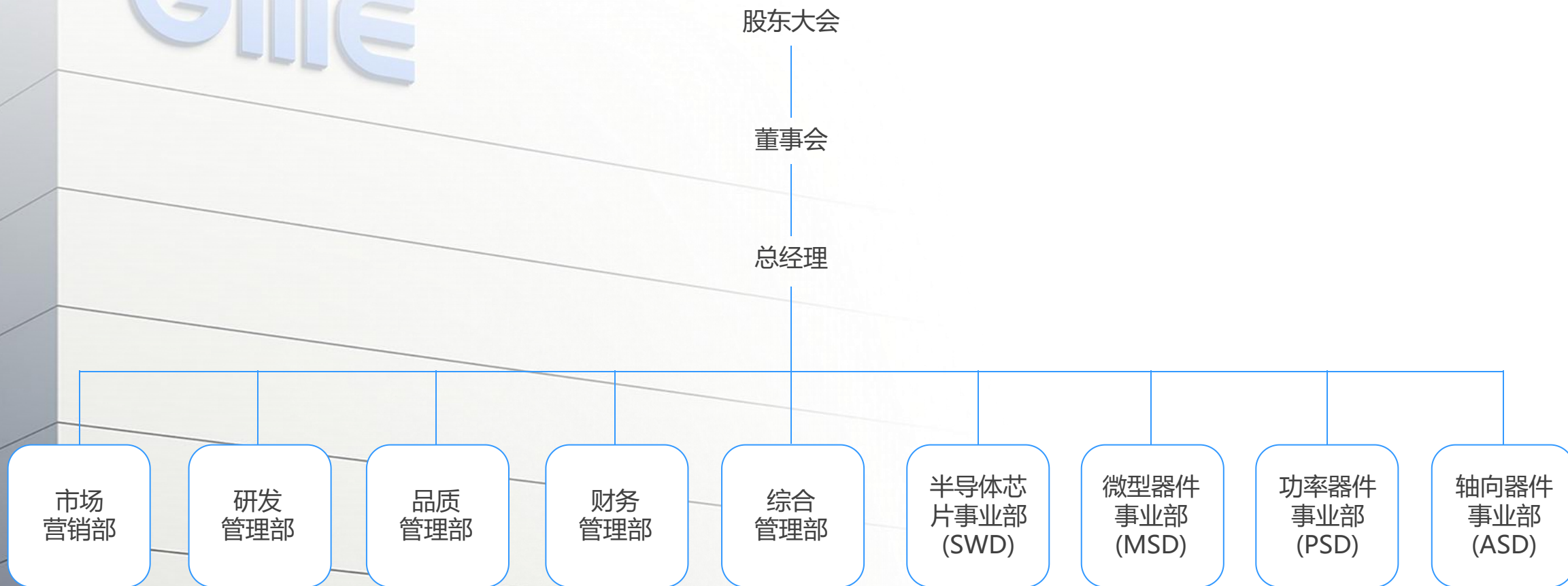


- ◎ **60余年**半导体行业制造经验
- ◎ 净化车间面积**5万m²**
- ◎ 公司员工人数超千人，服务团队超百人
- ◎ 研发团队由近**200**名专业技术人员组成
- ◎ 2020年至今累计研发投入**上亿元**
- ◎ 车规级产线投资**5亿**多元，实验室投资**上亿元**
- ◎ CNAS标准实验室投资**超亿元**
- ◎ 已获得国家有效专利**350**项，其中发明专利25项
- ◎ 掌握**20**多个门类、**100**多种封装外形产品的设计与制造工艺
- ◎ 量产**9000**多个规格型号的分立器件
- ◎ 细分行业内分立器件品种最为齐全的**领先企业**

- ◎ 累计服务**1000+**用户
- ◎ 客户包含近**30**家五百强企业
- ◎ 荣获BYD等**20+**知名客户颁发的优秀供应商证书
- ◎ 荣获 **CNAS** 证书
- ◎ 产品覆盖全国**30**多个省份及海外**50+**国家
- ◎ TVS、稳压二极管全国销量遥遥领先
- ◎ 功率器件年销量**30亿**只
- ◎ 车规级产品销量连续3年**200%**增长



组织架构



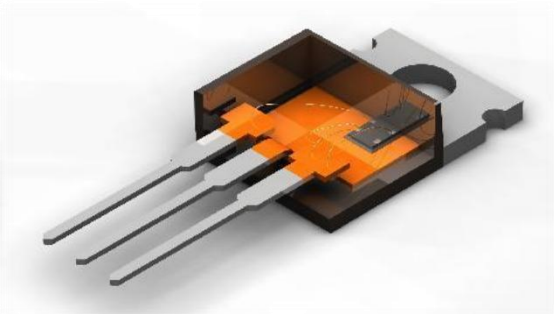
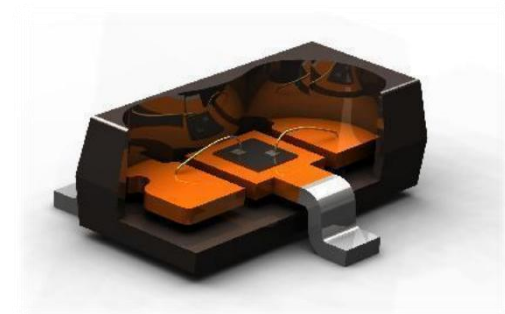
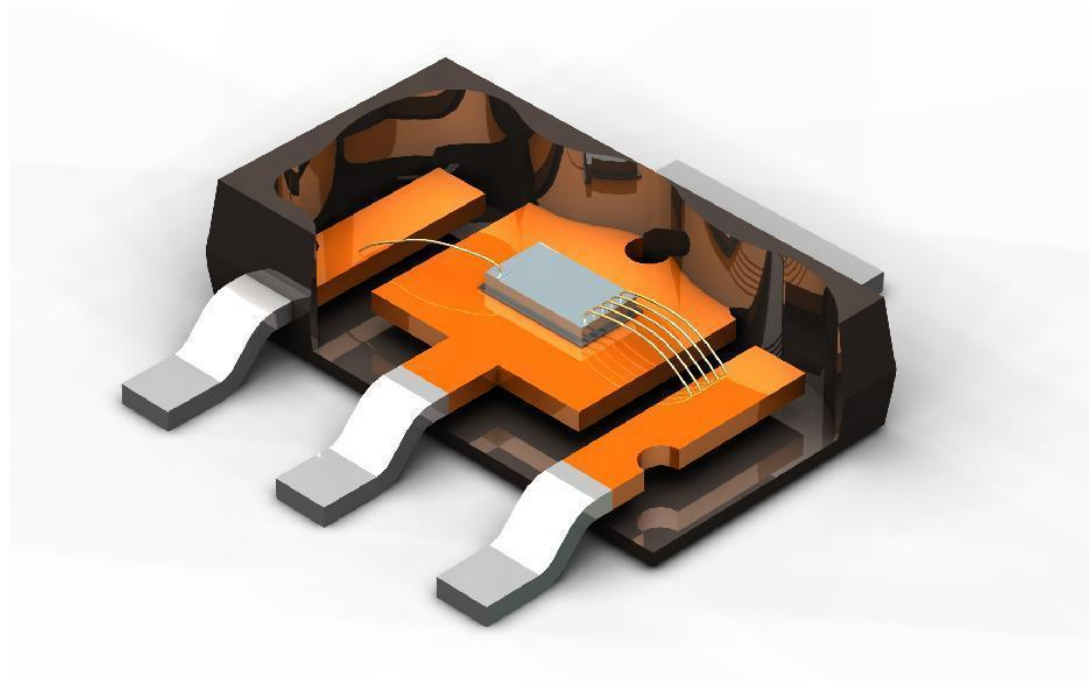
主要产品



公司专业从事半导体器件设计、芯片制造、封装测试、销售及服务。

| MOSFETsAEC-Q101 Partially (<100V) | Protection DevicesAEC-Q101 | Rectifying DevicesAEC-Q101 | TransistorsAEC-Q101 |
|---|---|---|--|
| Small Signal MOSFET L/M Voltage Power MOSFET <ul style="list-style-type: none">⊙ MOSFET (12V-250V)⊙ Dual MOSFETs (20V-100V) Trench & SGT | Surge Protection <ul style="list-style-type: none">⊙ TVS IEC 61000-4-5 SuperPlanar® ESD Protection <ul style="list-style-type: none">⊙ Zener⊙ ESD Diode/Array IEC 61000-4-2 | Diode / Rectifier <ul style="list-style-type: none">⊙ Bridge Rectifier (low V_F)⊙ General Purpose⊙ Fast Recovery⊙ Ultra Fast⊙ Super Fast⊙ Fast Recovery Epitaxial Diode (FRED) SuperPlanar® | <ul style="list-style-type: none">⊙ Bipolar Junction Transistor⊙ Digital Transistor⊙ RF Transistor |
| High Voltage Power MOSFET <ul style="list-style-type: none">⊙ VD MOSFET (400-1500V)⊙ Super Junction MOSFET Deep Trench Multi-epi | TPA | Schottky Diode / Rectifier <ul style="list-style-type: none">⊙ Planar SKY (30 ~ 250V)⊙ Trench SKY (20 ~ 250V)⊙ Planar MOSFET-SKY (150 ~ 300V)⊙ SiC Schottky 650V/1200V | Analog ICs <ul style="list-style-type: none">⊙ Linear Regulator⊙ LDO⊙ Voltage Reference |
| SiC MOSFETs <ul style="list-style-type: none">⊙ SiC MOSFET 650/1200V | IPM <ul style="list-style-type: none">⊙ SOP23H/DIP23H(IC+HV MOSFET/IGBT)⊙ 500V-650V 2A-5A | Small Signal Diode <ul style="list-style-type: none">⊙ Switching Diode⊙ Schottky Diode | Opto-electronic Devices <ul style="list-style-type: none">⊙ Opto-coupler DIP/SOP4 LSOP4 (Long Creepage)⊙ LED |
| GaN HEMT <ul style="list-style-type: none">⊙ GaN HEMT 650V | IGBT <ul style="list-style-type: none">⊙ Discrete⊙ 5A-50A⊙ 600/650V 1200V - 1350V Field StopTrench | RF Diode <ul style="list-style-type: none">⊙ PIN Diode⊙ Schottky Diode | |

Wire Bonding Product Line



PDFN3×3-8L



PDFN3×3-8LC



PDFN5×6-8L



PDFN5×6-8LC



TOLL



DFN8080



TO-252



TO-263



TO-220



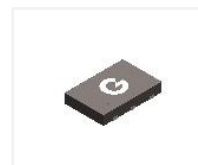
ITO-220



TO-247-2L/3L



TO-247-4L



DFN3020



DFN2510



DFN2020



DFN1010



DFN1006



DFN0603



SOT-143



SOT-323



SOT-89



DIP-4L



SOP-4L



LSOP-4L



SOP-8



SOD-123/323/523



SOT-563/723



SOT-23/3L/6L

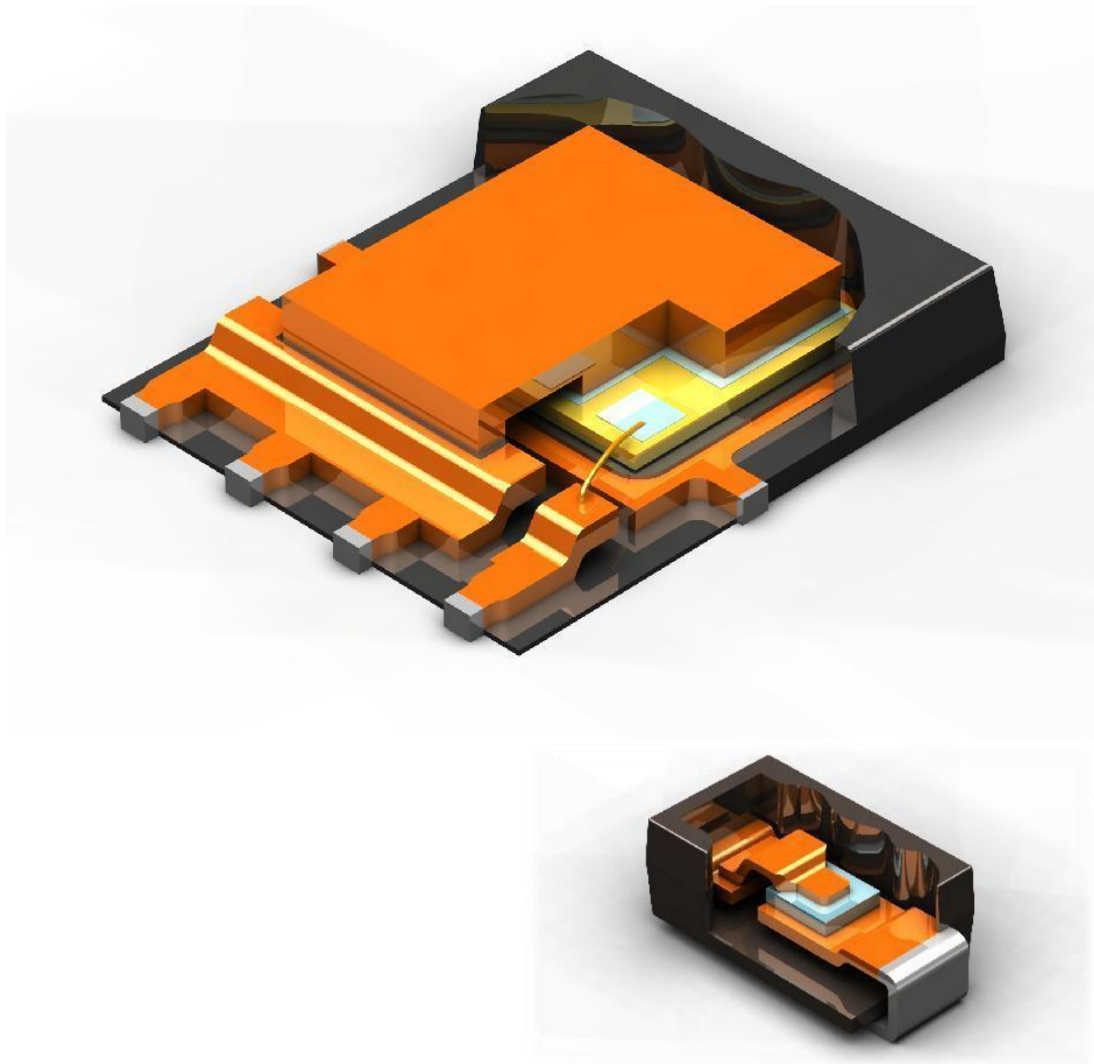



SOT-363/523



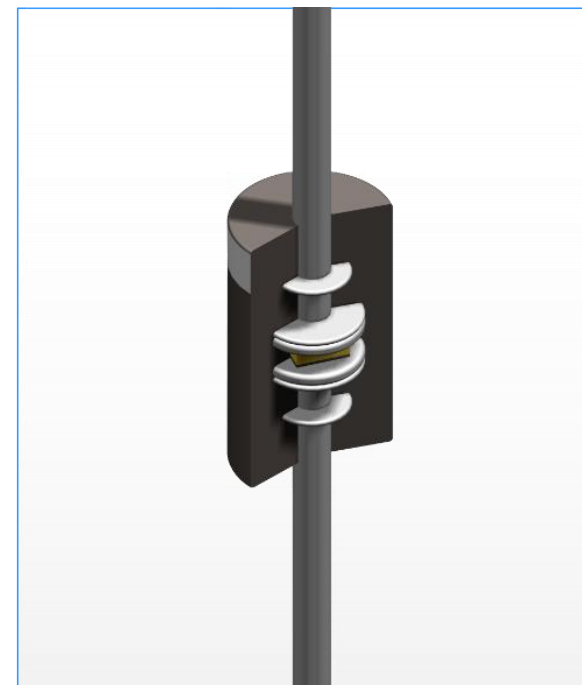
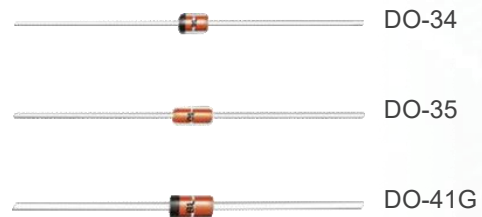
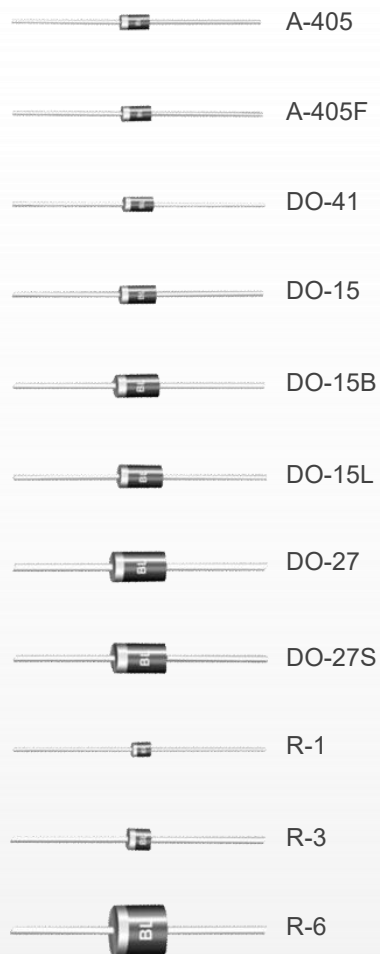
SOT-223

Clip Bonding Product Line



| | | | | | |
|---|---|---|---|---|---|
|  |  |  |  |  |  |
| PDFN5×6-8L | PDFN5×6-8L 双面散热 | SOD-323HE | SOD-323T | DO-218 | TO-277B |
|  |  |  |  |  |  |
| GBS | GBL | GBU | KBJ | GBJ | TDF |
|  |  |  |  |  |  |
| SOD-123FL / T | 3SPB | 5SPB | LB | MBF | TBF |
|  |  |  |  |  |  |
| SMA | SMB | SMC | SMAF | SMBF | SMCF |

Axial Welding Product Line



Road Map

微型化



DFN0603 (H=0.3mm)

CSP 0603
(H≤0.2mm)

more DFN Packages
(1.6x1.0; 1.6x1.6; 2.0x2.0; 8x6; 3.8x1.0)

FlipCSP 0603
(H≤0.2mm)

WLCSP ESD, SKY, MOSFET, LDO
Bump Technology

功率化



SOD-323T
Diodes

Power MOSFET
DFN5x6
TO-220 / 252
150~200V; 8~60A
15~300mΩ

Three Phase Bridge
20A -35A
1200-1600V

SiC JBS
TO-220 / 247 / 252
0.65~1.2 kV; 2~40A



DFN5x6
Dual-Cooling



DFN3X3 / DFN5X6
(Cu wire & Ribbon)



DFN3x3 / 5x6
Clip Bonding

IGBT
5-200A
650-1200-1500V

IGBT → Automotive

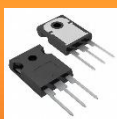
High Voltage MOSFET → Automotive

SiC MOSFET
650V/1200V/1700V

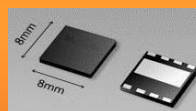
Planar TVS
 $P_{PP_MAX} = 8kW$



Gallium Nitride (GaN)
HEMT / MOSFET



TO-247
FRED/ Schottky/ HV MOSFET



DFN8x8
SiC Schottky / HV MOSFET



Automotive DFN5X6
Trench MOS Schottky

SiC JBS
1700V 40A



MOSFET in TOLL with lower R_{dson}



IPM 500V-650V
2A-5A SOP23H

SJ MOSFET
TO-220 / 247
TO-251 / 252 / 263
DFN8x8
600~900V; 2.5~53A
0.07~3.5Ω

Before 2024

2024

2024 Henceforth

量产

试产

规划

MOSFETs Roadmap

500V - 1700V HV Platform

1. Self-built 6/8 inch wafer production line to complete a full series of products ranging from 500V to 800V;
2. Complete 1000V~1700V special process series products;

80V - 100V Platform

Rdson 240mΩ~4.2mΩ Trench & SGT products

1. Further optimize $FOM=R_{don} \cdot Q_g$ and upgrade to Galaxy's 2nd Gen SGT products;
2. 1.4mΩ~3.9mΩ, TOLL, TO263-7 package products (including automotive grade certification);

60V Platform

Rdson 115mΩ~3.1mΩ Trench&SGT products

Rdson 1mΩ~3mΩ 12 inch wafer products
(including automotive grade certification);

40V Platform

1. Rdson 40mΩ~1.4mΩ Trench&SGT products
2. Dual channels MOSFET products
3. Automotive grade certification

1. Complete 12inch SGT MOSFET series (including more standard level Vth products)
2. Complete Rdson=0.5mΩ/0.7mΩ/0.8mΩ/1mΩ... Such as PDFN5X6, TO series package product development and automotive grade certification.
3. Increase the PDFN5X6 dual-cooling packaging series



20V - 30V Platform

1. 8 inch fab, Small signal SOT series package products;
2. 8 inch fab, Trench, Rdson can reach a minimum of 2.5mΩ;
3. Full range of automotive products

1. 12 inch wafers fully replace the original 8inch product series;
2. Complete all series products
3. Increase ESD protection series products;

Before 2024

2024

2024Henceforth

Power MOSFET

► Wide Range of Wafer Process Technology

- Trench MOSFET
- SGT MOSFET
- Planar VD-MOSFET
- Super-Junction MOSFET
- GaN E-HEMT

► Wide Range of Package Process Technology

- Conductive adhesive process
- Tin process
- Solder process
- Ball bonding process
- Welding process of aluminum wire
- Aluminum strip process
- Clip process

High Efficiency Design

A

► Capacity and Supply Security

Galaxy's MOSFET products are R&D independently, with strong production capacity from wafer to package, and has realized mass production of 12-inch MOSFET wafers, which can ensure the maximum security of supply.

► Flexibility

Galaxy has flexible supply chain planning, stocking and order adjustment to cope with demand fluctuations. We provide external storage resource allocation in case of emergency.

Secure Supply Chain

B

Package technology of Power MOSFET



SOT-223



TO-251



TO-252



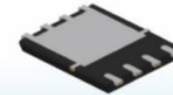
TO-263



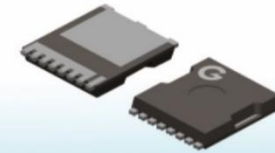
TO-220AB



PDFN3X3



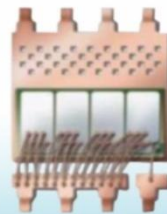
PDFN5X6



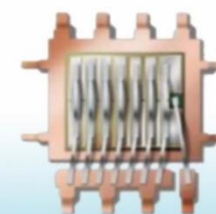
TOLL



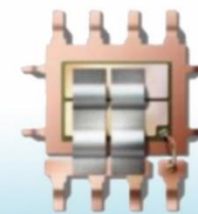
ITO-220



Copper wire bonding process



Aluminum wire bonding process



Aluminum tape bonding process



Clip process

研发布局



银河微电
Galaxy
Microelectronics

晶圆技术

常州

- ◉ GPP 生产工艺
- ◉ Planar 生产工艺
- ◉ Trench 生产工艺 (新晶圆厂规划中)
- ◉ SGT 生产工艺 (新晶圆厂规划中)
- ◉ Multi-epi 生产工艺 (新晶圆厂规划中)
- ◉ SiC 晶圆 生产工艺 (新晶圆厂规划中)

杭州

- ◉ 浙江创芯集成电路 ICsprout12吋 (55nm制程)战略合作

封装技术

常州

- ◉ 微型贴片器件
- ◉ 功率器件/模块
- ◉ 光电器件
- ◉ 射频器件
- ◉ 宽禁带SiC/GaN器件

芯片研发

上海

- ◉ 中高压MOSFET芯片
- ◉ IGBT芯片

台湾

- ◉ Trench肖特基芯片
- ◉ 低压MOSFET芯片
- ◉ IC芯片

常州

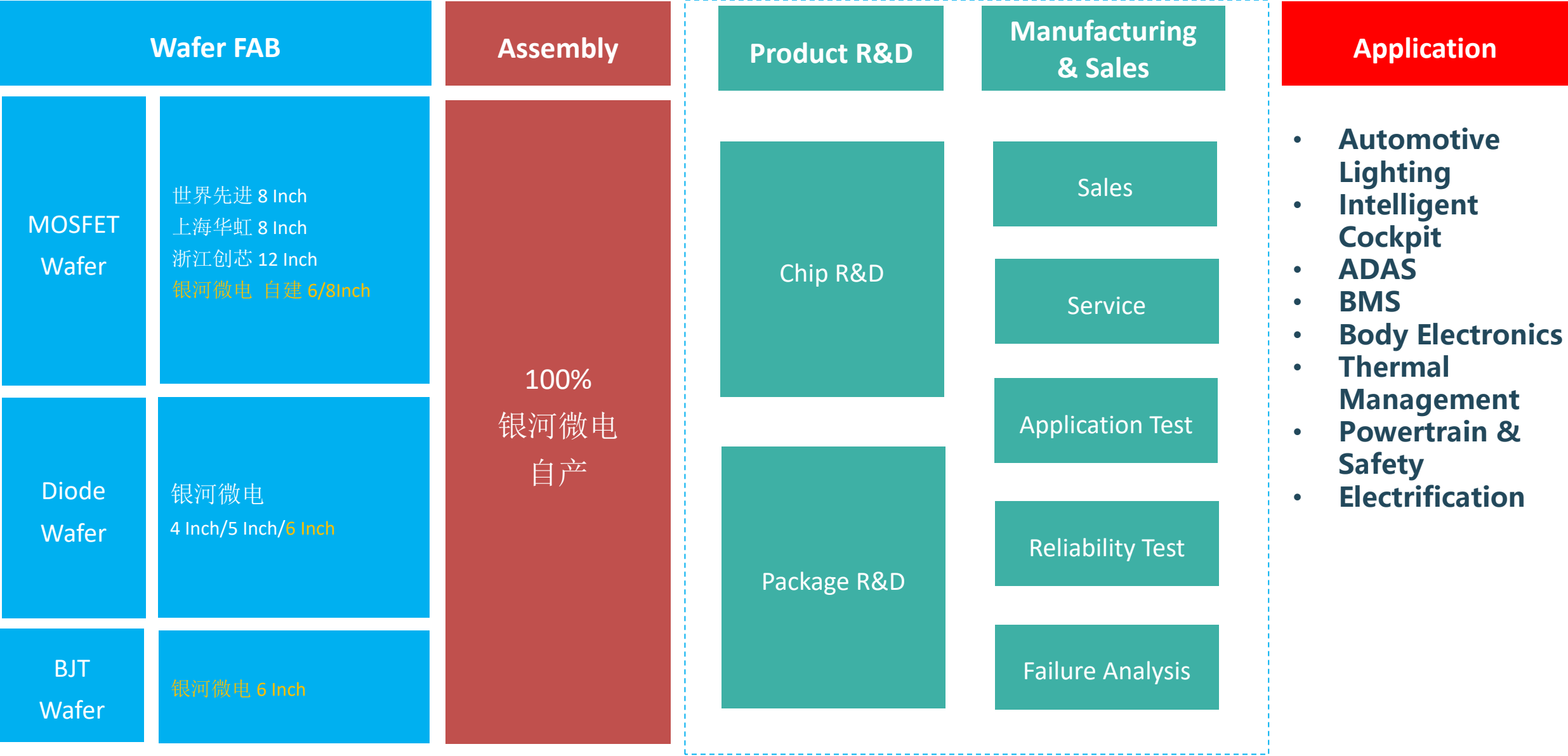
上海

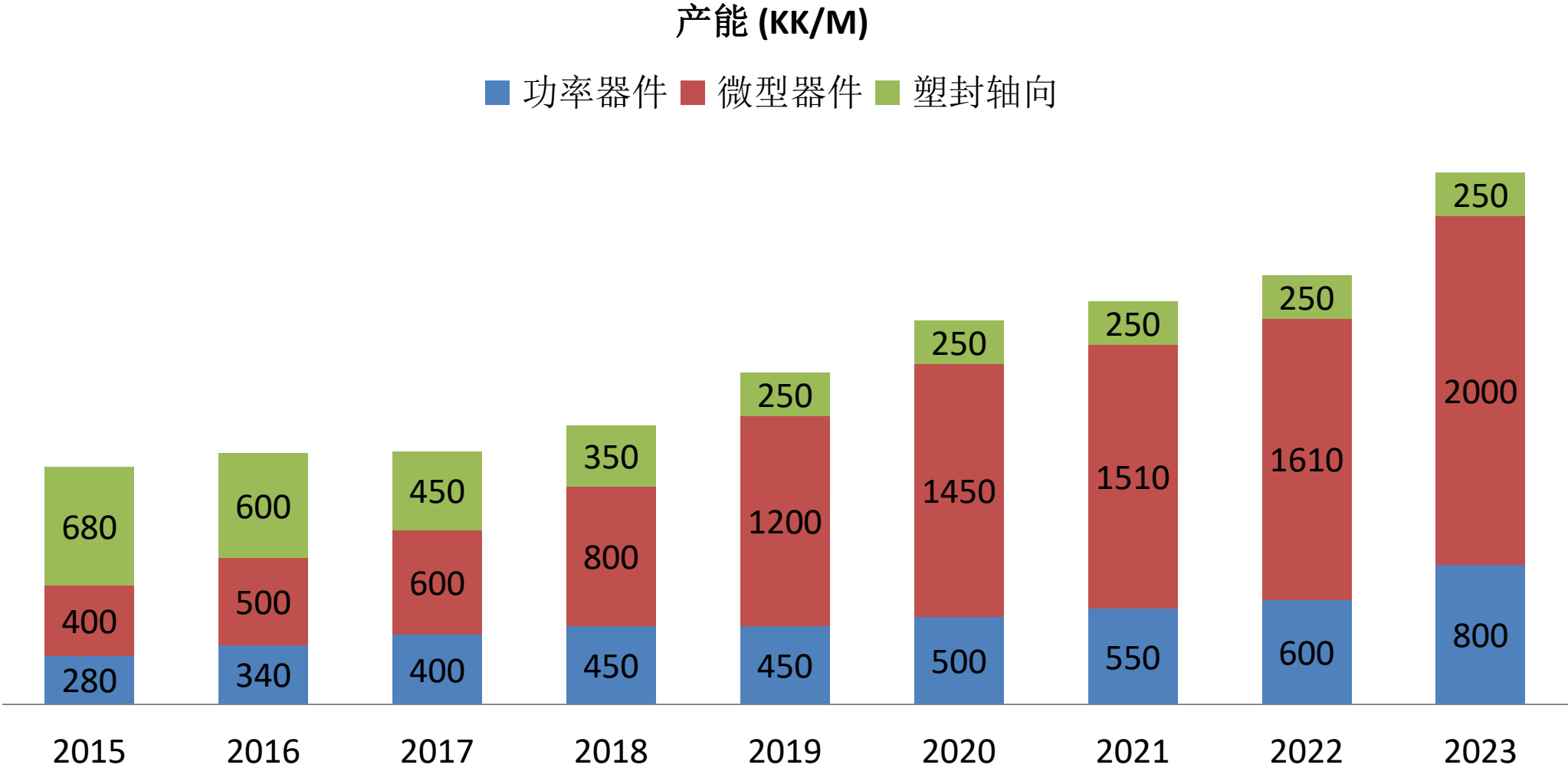
杭州

台湾

在常州、杭州、上海、台湾设有研发中心

拥有多支经验丰富的研发团队，致力于MOSFET芯片，IGBT芯片，IC芯片，第三代宽禁带半导体碳化硅(SiC)、氮化镓(GaN)等产品的芯片设计开发工作，并利用当地的半导体制程完成芯片的流片。





客户群

家电



能源动力



网络通信



工业自动化



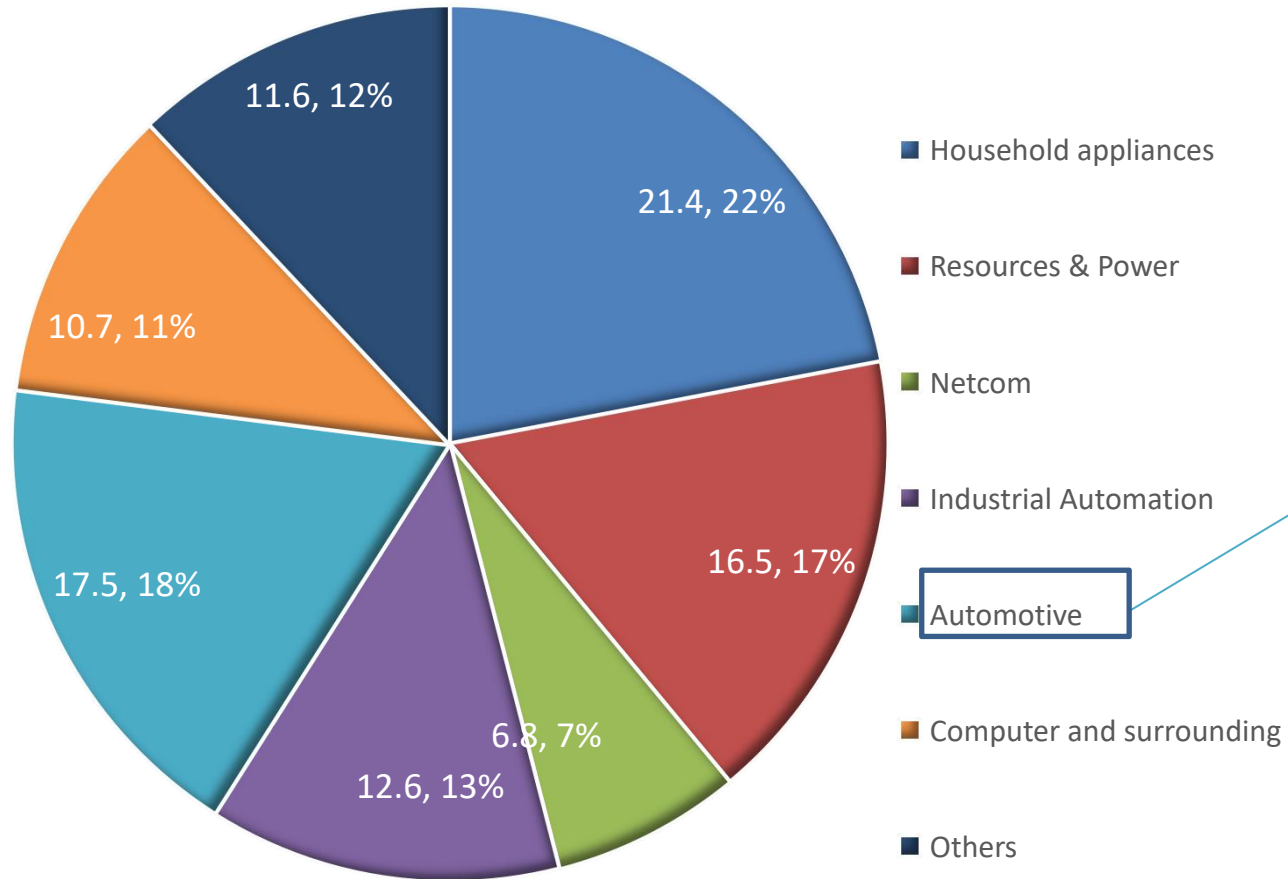
汽车电子



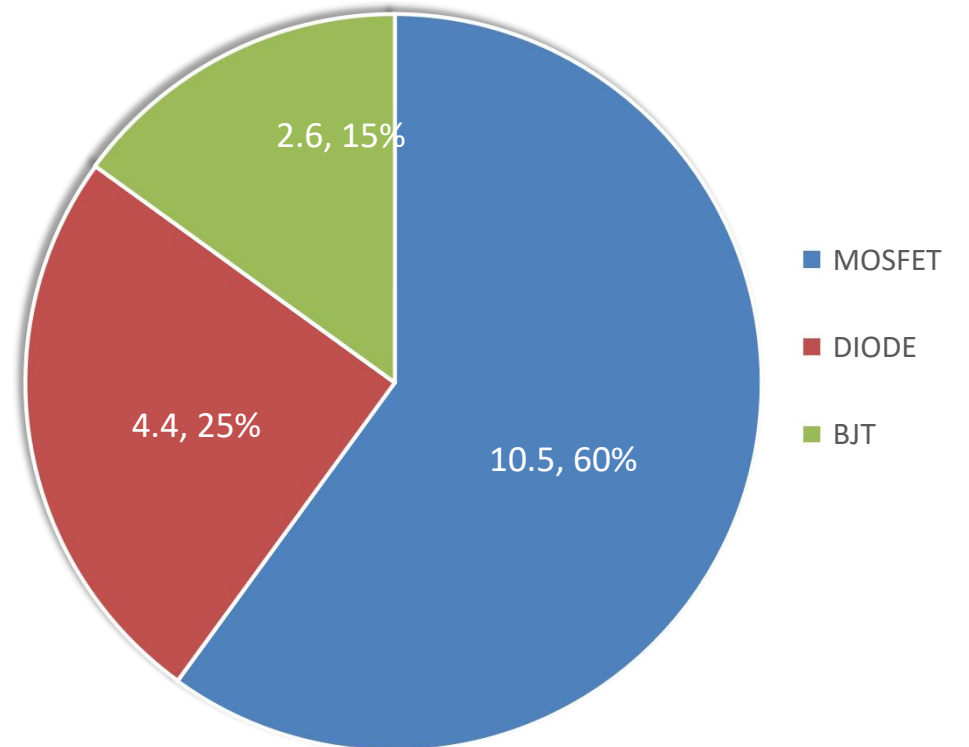
电脑及周边



ALLOCATION OF SALES BY MARKET 2023



ALLOCATION OF SALES BY AUTOMOTIVE PRODUCT



品质管控:国际认证证书

Automotive Electronics Council Component Technical Committee

March 13, 2018

David Chien
Changzhou Galaxy Century Microelectronics Co., Ltd.
Changzhou ,Jiangsu , China

Dear David,

On behalf of the AEC Component Technical Committee, it is my pleasure to inform you that Galaxy application for technical membership has been APPROVED. In order to update the AEC website, please forward your company logo (JPEG format or equivalent, <100kB in size) and contact information (for both the primary & alternate representative, if applicable). This information will be posted on the AEC website at www.aecouncil.com.

As a technical member of the AEC, you are invited to become a part of all on-going AEC activities. A listing of these activities and subteams are attached along with the member listing. We look forward to your ideas and participation. Committee conference calls to discuss new and ongoing AEC business are usually held every two to four weeks at 10:30AM U.S. Eastern Time and last 90 minutes. Formal meeting announcements (with the latest meeting minutes) will be forwarded to you via email as they are scheduled.

The cost of membership is an equal share of the funding of the Reliability Workshop we jointly hold each year in April. This will fluctuate depending on next year's workshop costs and the number of active members, but this year's cost will likely be around \$400.

Membership requirements are that you participate in technical committee and subteam calls as best you can and vote on balloted specs. If a company is inactive for a year (no call participation, no ballot voting), they may be considered for removal from the Technical Committee. Further details can be found in the attached AEC Charter. An organization chart on council support functions is also attached for your consideration in participation.

On behalf of the AEC Sustaining Members and the entire AEC Technical Committee, we welcome you to the AEC Component Technical Committee. If you have any questions or would like further information, please feel free to contact me or any AEC Committee Member.

Regards,

Robert V. Knoell

Bob Knoell
AEC Coordinator
NXP Semiconductors
bob.knoell@nxp.com
+1-248-880-6110

Automotive Electronics Council
Component Technical Committee

• APTIV •

BOSE

Continental

Cummins

Delphi
Technologies

DENSO

GENTEX
CORPORATION

HARMAN

HELLA

JOHN DEERE

KOSTAL

CYPRESS
PERIOD

DiR Solutions
reliability designed, reliability delivered

DIODES
CORPORATION

DOMINANT
Opto Technologies
Innovating Illumination

elmos

银河微电
Galaxy
Microelectronics

GLOBALFOUNDRIES

INDIUM
CORPORATION

infineon

- [AEC History](#)
- Updated: [AEC Members](#)
- Updated: [AEC Documents](#)
- [Selected Technical Papers](#)
- [Links to Related Web Sites](#)
- Updated: [2020 Annual AEC Reliability Workshop](#)
- [Contact the Technical Committee](#)

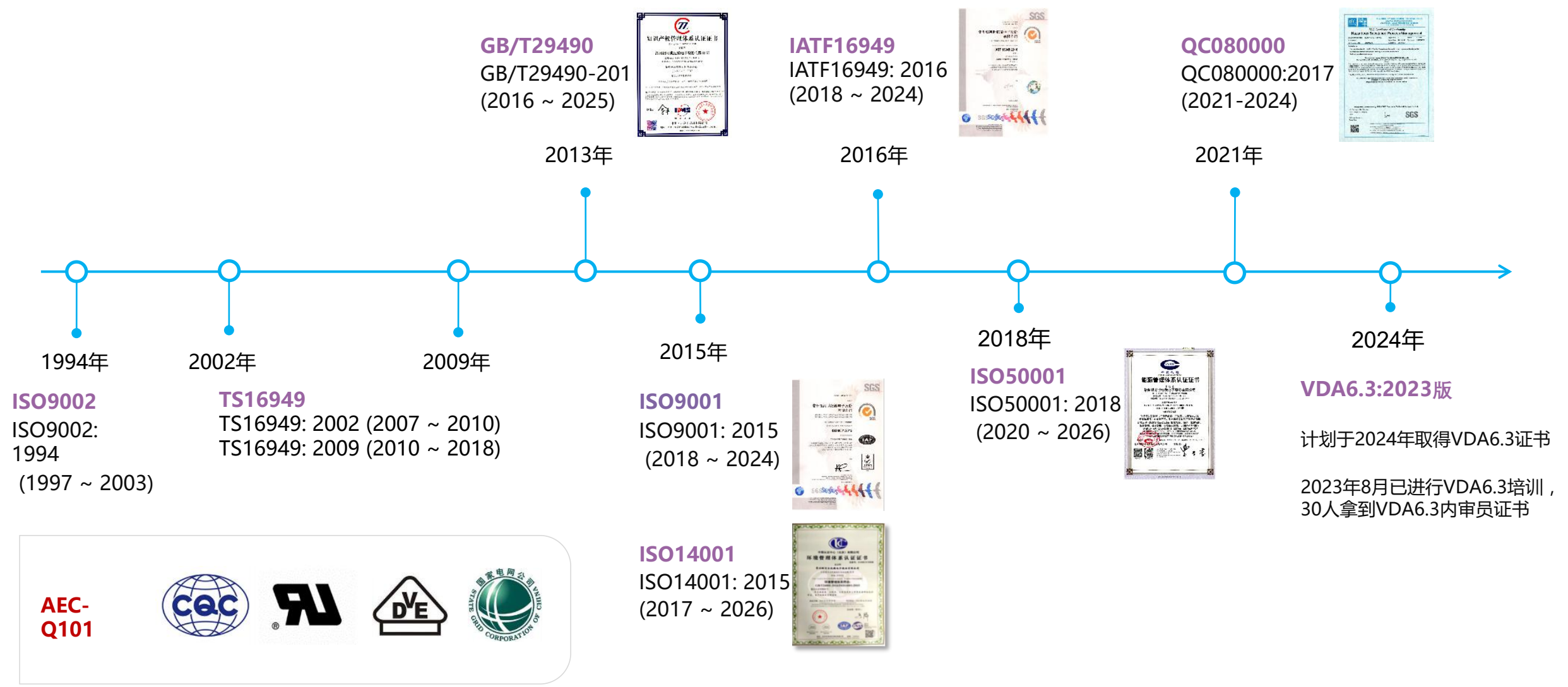


The Automotive Electronics Council (AEC) was originally established by Chrysler, Ford, and GM for the purpose of establishing common part-qualification and quality-system standards. From its inception, the AEC has consisted of two Committees: the Quality Systems Committee and Component Technical Committee. Today, the committees are composed of representatives from the Sustaining Members (currently Aptiv, Bose Corporation, Continental Corporation, Cummins, Delphi Technologies, Denso International America, Gentex Corporation, Harman, Hella, John Deere Electronics Solutions (Phoenix International), Kostal Automotive, Lear Corporation, Magna Electronics, Sirius XM, Valeo, Visteon Corporation and ZF) and other Technical, Associate, and Guest Members.

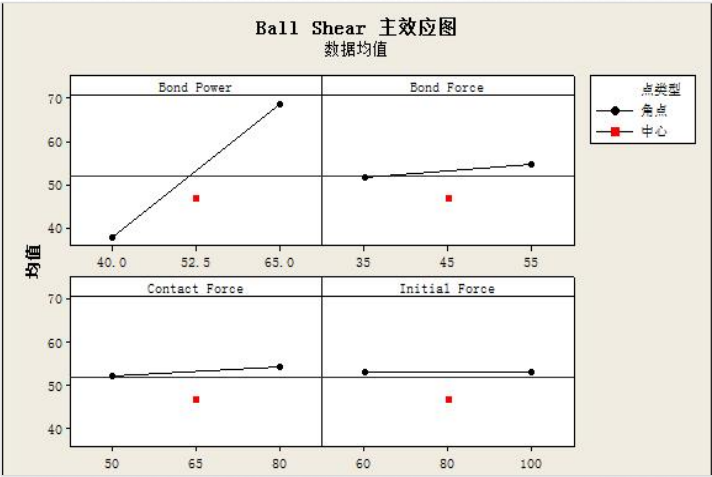
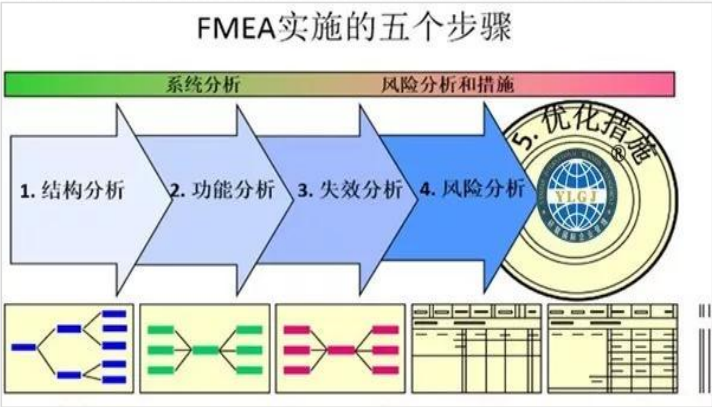
The AEC Component Technical Committee is the standardization body for establishing standards for reliable, high quality electronic components. These specifications are suitable for use in the harsh automotive environment without additional component-level qualification testing. This web site makes available the technical documents developed by the AEC Component Technical Committee. These documents can be downloaded directly.

品质管控:国际认证体系

以“客户需求为关注焦点”，全面贯彻国际标注化管控体系，充分运用APQP、FMEA、PPAP、MSA、SPC、DOE、PAT、SBL、SYL等工具，全方位管控产品实现的各个过程环节，确保提供客户满意的产品和服务。

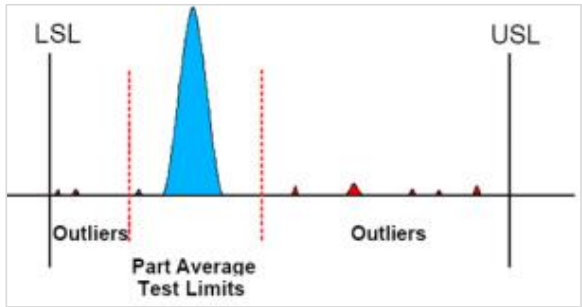


品质源于设计：产品研发严格遵守APQP管理流程，充分运用FMEA、DOE、防呆等管理技术，从源头确保品质。



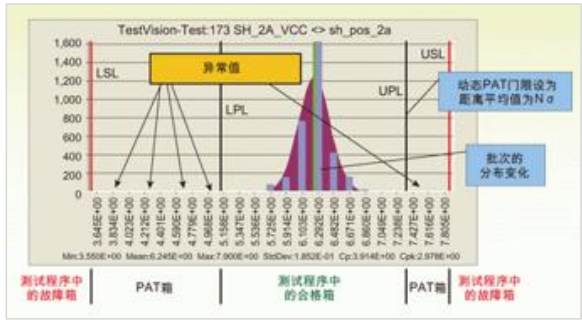
在TMTT导入PAT管理工具，剔除临界风险产品，大幅度降低产品早期失效。

PAT定义

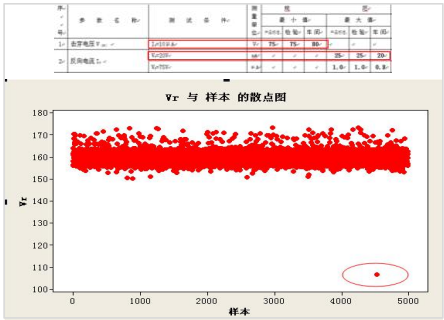


二极管：
 V_F 、 I_R 、 V_R
三极管：
 I_{CBO} 、 I_{CEO} 、 V_{CES} 、 V_{BES} 、 h_{FE}
MOSFET：
 I_{DSS} 、 I_{GSS} 、 $R_{DS(ON)}$ 、 V_{SD} 、 $V_{(TH)}$

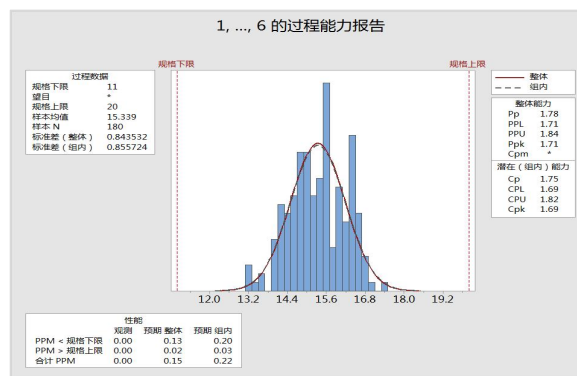
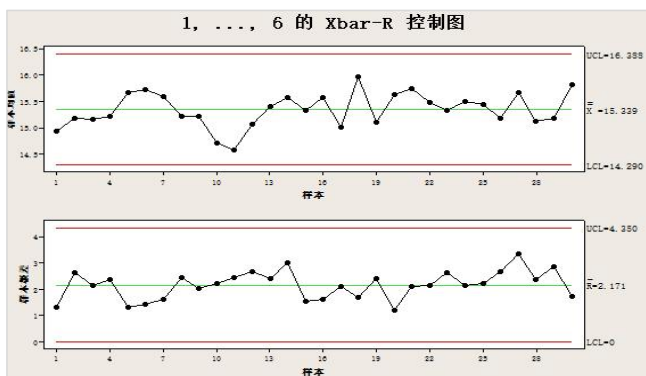
测试分选机中的Bin箱



实例



关键质量控制点推行MSA、SPC统计技术，
设置限度样品、标准样品管理，制程品质实时监控。



| 文件名称 | 分立器件装片质量标准 | 过程名称 | 装片 | 过程编号 | M03 | 版本/修订 | E/0 |
|------|----------------------|------|------------|------|-----|-------|-----|
| 文件编号 | GME/JS-SIP-MP-002-01 | 适用范围 | 适用于装片的质量检验 | | | | |
| | | | | | | | |
| | | | | | | | |

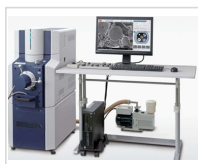
图1: 歪管 (转角 $\geq 5^{\circ}$) 图2: 色管、墨点片 图3: 空管 图4: 碎管 图5: 装片叠料

| 管控项目 | 管控方法 | 检验设备 |
|--------|-----------|-------------|
| 芯片厚度 | Xbar-R控制图 | 厚度测试计 |
| 氧化层膜厚 | Xbar-R控制图 | 膜厚仪 |
| 光刻胶膜厚 | Xbar-R控制图 | 膜厚仪 |
| 划片刀痕宽度 | Xbar-R控制图 | 测量显微镜 |
| 点胶直径 | Xbar-R控制图 | 测量显微镜 |
| 焊线拉力 | Xbar-R控制图 | DAGE4000测试仪 |
| 焊球厚度 | Xbar-R控制图 | 测量显微镜 |
| 线弧高度 | Xbar-R控制图 | 测量显微镜 |
| 镀层厚度 | Xbar-R控制图 | 镀层测厚仪 |
| 站立高度 | Xbar-R控制图 | 投影仪 |
| 编带拉力 | Xbar-R控制图 | 剥离强度测试仪 |

我们拥有经验丰富的专业人员，齐全的检测、试验与分析设备。

产品及过程监控设备

◉ 在制产品结构分析 ◉ 封测产品结构分析 ◉ 产品电性能测试



SEM扫描仪



SAM扫描仪



X-RAY检测仪



功率器件测试仪



焊线拉力测试仪



光学显微镜



研磨仪



激光开封机



易焊性分析仪

可靠性试验设备

◉ 环境及机械耐受能力 ◉ 寿命加速试验



寿命试验箱



恒流老化箱



高温反偏试验箱



冷热冲击试验箱



高压蒸煮试验台



高加速应力测试仪



间歇寿命测试仪



回流焊



波峰焊

应用模拟试验设备

◉ 产品电性能 ◉ 应用模拟分析 ◉ 失效分析



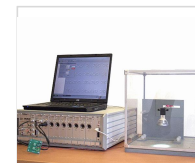
雷击测试仪



振铃测试仪



ESD测试仪



T3STER瞬态电阻测试器



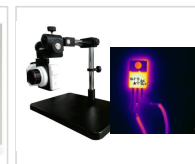
可编程交流/直流电源



直流可编程电子负载



示波器



红外热成像仪



电路在线测试

可靠性试验参考标准：AEC-Q101-E版

实验室通过ISO17025认证：



| 分组 | 序号 | 项目缩写 | 项目全称 | 试验条件 | 时间 | 批数 | 样本量 (pcs) | 失效数 (pcs) | 参考文献 |
|----------------|-------|--------|------------|---|--------------|----|-----------|-----------|-------------------------------|
| A组 加速环境应力测试 | 1 | PC | 预处理 | 1、TCT 5 cycles, -55~150℃, 15min; 2、Baking 125℃ 24 hrs; 3、Soaking: 85℃/85% RH 168hrs (MSL 1) or 30℃/60% RH 192hrs (MSL 3); 4、IR reflow 260℃ 3 cycles | - | 3 | 338 | 0 | JESD22-A113 |
| | 2 | *HAST | 高加速寿命试验 | T _a =130℃, 85%RH, V = 80%V _R or 1200V(Max) | 96h | 3 | 77 | 0 | JESD22-A110 |
| | 2 alt | *H3TRB | 高温高湿反偏 | T _a =85℃, 85%RH, V = 80%V _R or 800V(Max) | 1000h | 3 | 77 | 0 | JESD22-A101 |
| | 3 | *IOL | 间歇寿命 | ΔT _j ≥100℃, on 2mins, off 2mins | 15000 cycles | 3 | 77 | 0 | MIL-STD-750 Method 1037 |
| | 4 | *AC | 高压蒸煮 | T _a =121℃, 100%RH, 0.20 Mpa | 96h | 3 | 77 | 0 | JESD22-A102 |
| | 4 alt | *UHASt | 无偏置高加速寿命 | T _a =130℃, 85%RH, no bias | 96h | 3 | 77 | 0 | JESD22-A118 |
| | 5 | *TC | 温度循环 | T _{stg} (Min)~T _{stg} (Max), t _{dwell} >15 min | 1000 cycles | 3 | 77 | 0 | JESD22-A104 |
| | 5 a | TCHT | 温度循环后热测试 | 125℃ TEST after TC, followed by decape and wire pull | | 3 | 77 | 0 | JESD22-A104 Appendix 6 |
| B组 加速寿命测试 | 5 b | TCDT | 温度循环后DPA分析 | 100% AM inspection after TC, followed by decape or wire pull | | 3 | 77 | 0 | JESD22-A104 Appendix 6 |
| | 6 | HTRB | 高温反偏 | T _j =T _j (Max), V = 100%V _R (Max) | 1000h | 3 | 77 | 0 | MIL-STD-750 M1038 condition A |
| | 7 | HTGB | 高温栅偏 | T _a =T _j (Max), V = 100%V _{GS} (Max) | 1000h | 3 | 77 | 0 | JESD22-A108 |
| | 8 | SSOP | 稳态寿命 | I=I _{zmax} , T _A =rated T _j | 1000h | 3 | 77 | 0 | MIL-STD-750 M1038 condition B |

可靠性试验参考标准：AEC-Q101-E版

实验室目前可独立可完成

AEC-Q101

AEC-Q006



A23083006
CHM84ESGI



A23063007
THELBL0271

合作的第三方实验室：



| 分组 | 序号 | 项目缩写 | 项目全称 | 试验条件 | 时间 | 批数 | 样本量 (pcs) | 失效数 (pcs) | 参考文献 |
|-------------------------|----|------|---------|---|-------|----|-----------|-----------|--|
| C组 封装组 件完整 性测试 | 9 | DPA | 破坏性物理分析 | Post H3TRB or HAST and TC | | 1 | 2 | 0 | AEC Q101-004 Section 4 |
| | 10 | PD | 尺寸测量 | Verify physical dimensions to specifications | | 1 | 30 | 0 | JESD22-B100 |
| | 11 | WBP | 焊线强度 | | | 1 | 10 | 0 | MIL-STD-750-2 Method 2037 for Au and Al wire AEC Q006 for Cu wire |
| | 12 | WBS | 推球强度 | | | 1 | 10 | 0 | JESD22-B116 |
| | 13 | DS | 推晶强度 | | | 1 | 5 | 0 | MIL-STD-750 Method 2017 |
| | 14 | TS | 热疲劳 | | | 1 | 30 | 0 | MIL-STD-750-2 Method 2036 |
| | 15 | RTS | 印字牢度 | Verify marking permanency. Not required for laser marking | | 1 | 30 | 0 | JESD22-B107 |
| | 16 | RSH | 耐焊接热 | 260 (+5/-0)°C | 10±1s | 1 | 30 | 0 | JESD22-A111 (SMD) or B-106 (PTH) |
| | 17 | TR | 热阻 | per device specification, | | 1 | 10 | 0 | JESD24-3, 24-4, 24-6 as appropriate |
| | 18 | SD | 可焊性 | Wet balance / 245±5°C | 5sec | 1 | 25 | 0 | J-STD-002 |
| E组 电气验 证测试 | 19 | WG | 锡须 | | | 1 | 9 | 0 | AEC-Q005 |
| | 20 | EV | 外观检查 | Device construction, marking, and workmanship | | 3 | all | 0 | JESD22-B101 |
| | 21 | TEST | 电性测试 | | | 3 | all | 0 | User specification or supplier's standard specification |
| | 22 | PV | 三温测试 | TEST @-55°C, 25°C, 125°C | | 3 | 25 | 0 | Individual AEC user specification |
| | 23 | ESDH | 静电HBM | | | 1 | 30 | 0 | AEC Q101-001 |
| | 24 | ESDC | 静电CDM | | | 1 | 30 | 0 | AEC Q101-005 |
| | 25 | UIS | 非钳位电感开关 | | | 1 | 5 | 0 | AEC Q101-004 Section 2 |

FA分析流程

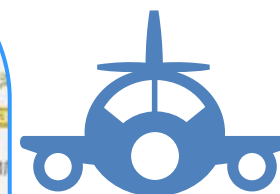


持续提升

围绕品质、效率（交期）提升，组织现场作业人员成立专项小组，从实际出发，遵循现场现物、实事求是、灵活多样之原则，持续改善现行管理系统。



地理位置



常州奔牛机场
无锡硕放机场
南京禄口机场
上海虹桥/浦东机场



常州北站(高铁)
常州火车站



G42沪蓉高速
常州/薛家出口



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